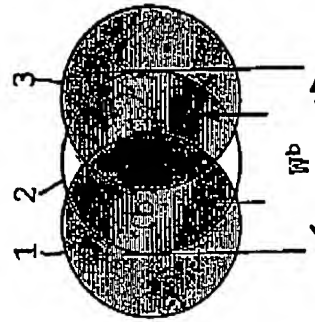
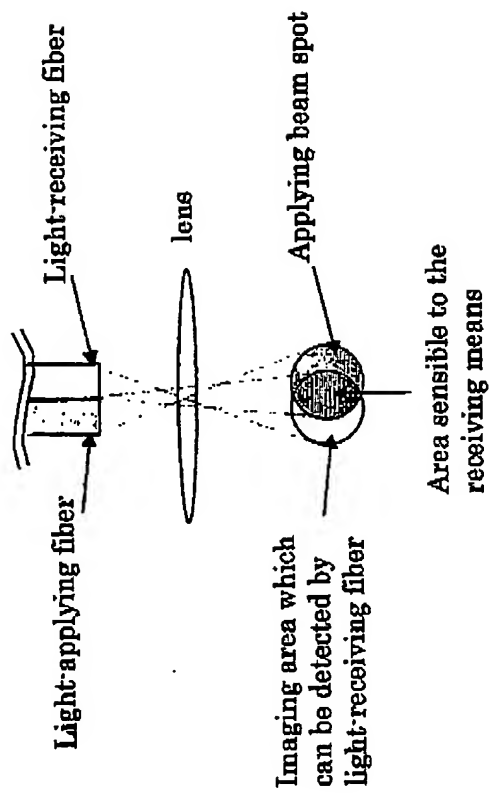
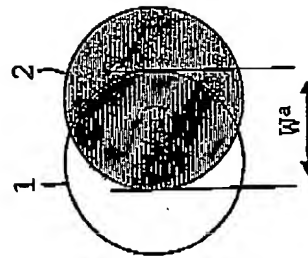


Response to Office Action
REFERENCE

REFERENCE FIG. A



REFERENCE FIG. C



REFERENCE FIG. B

Response to Office Action
REFERENCE

English translation of partial description of Toshiyasu et al., corresponding to the Phrase #0009 and #0011 of the Japanese description of JP 08-334471.

[0009]

[Function] In the first embodiment of the optical test equipment of the work piece, outgoing radiation of the inspection light from one light-applying fiber in at least one fiber bundle arranged in the tip portion of inspection optical member is carried out toward the work-piece front face which counters the above-mentioned tip portion of inspection optical member and is displaced relatively, and the reflected light is received into two or more light-receiving fibers of the above-mentioned fiber bundle. After receiving the reflected light with the photosensor arranged oppositely and correspondingly to the radiation edge of light-receiving fibers, each of which is classified into two of groups, and carrying out electrical-potential-difference conversion of that amount of reflected lights, by an inspection processor means, the difference of the output voltage from one photosensor relative to the electrical potential difference, which reversed the output voltage from the other photosensor, is asked for. Then, the difference in the electrical potential being compared with the threshold level preliminarily set up, the existence of adhesion of a blemish and a foreign matter on the above-mentioned work-piece front face is inspected.

[0011] Moreover, in the 1st and 2nd embodiment of the above optical test equipment of work piece, the tip portion of inspection optical member is constituted of a fiber array including two or more of said fiber bundle arranged in a array, thereby making it possible to inspect the work-piece front face per unit of array, the work-piece front face relatively moving along said inspection optical member.